Virtex-II Pro PowerPC SEE Characterization
Test Methods and Results

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Abstract

The Xilinx Virtex-II Pro is a platform FPGA that embeds multiple microprocessors within the fabric of an SRAM-based reprogrammable FPGA. The variety and quantity of resources provided by this family of devices make them very attractive for spaceflight applications. However, these devices will be susceptible to single event effects (SEE), which must be mitigated.

Observations from prior testing of the Xilinx Virtex-II Pro suggest that the PowerPC core has significant vulnerability to SEEs. However, these initial tests were not designed to exclusively target the functionality of the PowerPC, therefore making it difficult to distinguish processor upsets from fabric upsets. The main focus of this paper involves detailed SEE testing of the embedded PowerPC core. Due to the complexity of the PowerPC, various custom test applications, both static and dynamic, will be designed to isolate each unit of the processor. Collective analysis of the test results will provide insight into the exact upset mechanisms of the PowerPC. With this information, mitigations schemes can be developed and tested that address the specific susceptibilities of these devices.

The test bed will be the Xilinx SEE Consortium Virtex-II Pro test board, which allows for configuration scrubbing, design triplication, and ease of data collection. Testing will be performed at the Indiana University Cyclotron Facility using protons of varying energy levels and fluencies. This paper will present the detailed test approach along with the results.
XRTC Board – Daughter Card

- Xilinx Virtex-II Pro
  - XQR2VP40-FF1152
  - Dual PowerPCs
  - 15,868,256 configuration bits
- External interfaces
  - Platform flash devices
  - JTAG/SelectMAP
  - CPU debug headers
  - RS-232
  - 2 300-pin Teradyne connectors
  - SMPX MGTs
- Isolated power lugs

XRTC Board - Motherboard

- 2 XC2VP70 FPGAs
  - DUT configuration scrubber
  - DUT functionality monitor
- External interfaces
  - Platform flash devices
  - System ACE
  - Triple majority voted flash
  - 7 40-pin IDE connectors
  - 3 512-MB SDRAM DIMMs
  - 3 RS-232 ports
  - JTAG/Debug headers
  - MGT clock synthesizer
  - SMPX MGTs

Patrick

MAPLD05/P146
IUCF Test Facility

- Indiana University Cyclotron Facility
  - Bloomington, IN
  - Proton beam
    • Energy: 30 - 200 MeV
    • Flux: 1e2 – 1e11 p/sec-cm²
  - Cable length distance to user area is 60-70 ft.

Test Setup

- Laptop #1
  - PCMCIA GPIB
  - GPIB Extender
  - Power Supply #1 (3.3, 5)
  - LED Switch Box (ConfigMon)
- Laptop #2
  - LED Switch Box (FuncMon)
- Laptop #3
- Radiation Chamber
  - Power Supply #2 (2.5, 3.3)
  - Power Supply #3 (1.5, 2.5, 3.3)
  - SEAKR Motherboard
  - DUT Daughtercard
  - RS232
  - JTAG
Test Applications

1. Static Register/Cache Test
   - PowerPC initializes registers before each run
   - XMD used to initialize data cache before run, read out register and data cache after run via JTAG

2. “Pseudo-Static” Register Test
   - FuncMon issues IRQs to DUT PowerPC at 1-Hz
   - DUT PowerPC ISR dumps all 80 register values to FuncMon via 32-bit GPIO data bus
   - FuncMon buffers all data received, issues IRQ to its own PowerPC, which dumps data out UART
   - FuncMon also counts reset events and timeout events
Test Complications

- **Functionality not integrated for this test**
  1. Configuration scrubbing
  2. Design triplication
  3. DUT PowerPC exception handlers

- **Connection failures with socketed DUT card**
  - 1152-pin spring loaded socket
  - Damaged springs resulted in signal connections including JTAG
  - Static register/cache test was not possible with socketed card
SEE Results

Static Test Bit-Error Results

<table>
<thead>
<tr>
<th>PowerPC Unit</th>
<th>Total Bit-Errors</th>
<th>Cross (cm²)</th>
<th>StDev</th>
<th>Cross/bit (cm²)</th>
<th>StDev</th>
</tr>
</thead>
<tbody>
<tr>
<td>GPRs</td>
<td>4</td>
<td>4.99E-11</td>
<td>2.50E-11</td>
<td>4.88E-14</td>
<td>2.44E-14</td>
</tr>
<tr>
<td>D-Cache</td>
<td>87</td>
<td>4.34E-9</td>
<td>2.33E-10</td>
<td>3.31E-14</td>
<td>1.78E-15</td>
</tr>
</tbody>
</table>

Pseudo-Static Test SEE Results

(Note: Each run was stopped when the DUT stopped responding to IRQs)

<table>
<thead>
<tr>
<th>Computation Method</th>
<th>Cross (cm²)</th>
<th>StDev</th>
</tr>
</thead>
<tbody>
<tr>
<td>Average of 24 runs</td>
<td>9.54E-10</td>
<td>7.51E-10</td>
</tr>
</tbody>
</table>

- Other observed effects:
  - Processor resets, DUT power cycling required, instruction jumps, program exceptions, irregular response to IRQs, bit-flips in SPRs

Discussion of Results

- Static Test
  - Valid SEU data collected on register and cache
  - For statistical purposes, more testing is required
  - Scrubbing will keep JTAG routing valid, decreasing the number of "bad" runs

- Pseudo-Static Test
  - The runs were not long enough to gather SEU data on the registers
  - Four runs failed during a DUT PowerPC ISR, however:
    - No scrubbing → all runs most likely failed due to configuration upsets rather than a PowerPC SEE
    - Scrubbing and exception handlers will allow SEU data to be collected using this IRQ design scheme
Future Work Plan

- Integrate configuration scrubbing, exception handlers, and TMR into designs
- Add more functionality to test applications
  - Use of dual PowerPCs for data collection
  - Ability to monitor/count program exception types
- Advanced test applications
  - Exercise PowerPC with dynamic test
  - Preliminary PowerPC mitigation test
- Next test date: October 17-19 @ IUCF

Dynamic Test

- Purpose: to monitor the PowerPC's effectiveness to continuously execute instructions and maintain its functionality
- Run multiple functions
  - Time-of-Day computation
  - Matrix math operations
  - Memory operations
- DUT command and status
  - Monitor DUT via GPIO bus and other critical status lines (e.g. ICURequest, MachineCheck)
  - Control DUT functionality via GPIO; revive DUT PowerPC using IRQs and resets
  - Post-run memory/register dump via JTAG
- Conduct tests over range of clock frequencies
Mitigating Dual PowerPCs

Two levels of mitigation:
1. Each PowerPC needs individual software mitigation schemes
2. Additional hardware layer needed to compare results from both PowerPCs, and detect and correct PowerPC SEEs

- Hardware Architecture
  - Tripliication data paths
  - PowerPC controller core
    - Compare PowerPC results
    - Monitor PowerPC health
    - Schedule PowerPC servicing
    - Log data and PowerPC state info
  - Command handshaking
    - Between core and each PowerPC
    - Between PowerPCs

- Software Application
  - Both processors run identical code
  - Code replication
    - Data duplication
    - Branch duplication
    - Result duplication
  - Checkpoints and rollback
  - Heartbeat generation
  - Watchdog

Possible Mitigation Architecture